

Title (en)
ANALYTICAL TESTING ELEMENT AND METHOD FOR THE MANUFACTURE THEREOF

Title (de)
ANALYTISCHES TESTELEMENT UND VERFAHREN ZU DESSEN HERSTELLUNG

Title (fr)
ÉLÉMENT DE TEST ANALYTIQUE ET PROCÉDÉ POUR SA FABRICATION

Publication
EP 2307139 A1 20110413 (DE)

Application
EP 09797481 A 20090713

Priority

- EP 2009058893 W 20090713
- EP 08160317 A 20080714
- EP 09797481 A 20090713

Abstract (en)
[origin: EP2145683A1] An analytic test element (10) comprises a surface designed as a chemical verification layer (14) and a spreading net (16). The spreading net is disposed on the chemical verification layer for planar distribution of a liquid sample. The spreading net comprises an oxidized metallic layer (20) at the surface of the net facing the verification layer. The oxidized metallic layer is oxidized with an oxygen or sulfur-oxidizing agent.

IPC 8 full level
B01L 3/00 (2006.01)

CPC (source: EP US)
B01L 3/5023 (2013.01 - EP US); **G01N 33/525** (2013.01 - EP US); **B01L 2300/0887** (2013.01 - EP US); **B01L 2300/161** (2013.01 - EP US); **B01L 2400/0406** (2013.01 - EP US); **Y10T 156/10** (2015.01 - EP US); **Y10T 428/23986** (2015.04 - EP US); **Y10T 442/20** (2015.04 - EP US); **Y10T 442/2484** (2015.04 - EP US)

Citation (search report)
See references of WO 2010007014A1

Citation (examination)

- GB 2065302 A 19810624 - FUJI PHOTO FILM CO LTD
- US 6555061 B1 20030429 - LEONG KOON-WAH [US], et al

Designated contracting state (EPC)
AT BE BG CH CY CZ DE DK EE ES FI FR GB GR HR HU IE IS IT LI LT LU LV MC MK MT NL NO PL PT RO SE SI SK SM TR

Designated extension state (EPC)
AL BA RS

DOCDB simple family (publication)
EP 2145683 A1 20100120; CA 2730402 A1 20100121; CA 2730402 C 20160712; CN 102099118 A 20110615; EP 2307139 A1 20110413; JP 2011528114 A 20111110; JP 2016138893 A 20160804; KR 101656894 B1 20160912; KR 20110040834 A 20110420; MX 2011000293 A 20110302; US 2012020839 A1 20120126; US 2012315432 A1 20121213; US 8263020 B2 20120911; US 8586377 B2 20131119; WO 2010007014 A1 20100121

DOCDB simple family (application)
EP 08160317 A 20080714; CA 2730402 A 20090713; CN 200980127419 A 20090713; EP 09797481 A 20090713; EP 2009058893 W 20090713; JP 2011517885 A 20090713; JP 2016067921 A 20160330; KR 20117000936 A 20090713; MX 2011000293 A 20090713; US 201113005832 A 20110113; US 201213588494 A 20120817